

We claim:

1. A method of correcting defective pixels of an image sensor, which comprises:

depending on a defect signal, outputting input pixel data as output pixel data in a defect-free case and outputting pixel data interpolated from adjacent pixel data as output pixel data in a defect case;

generating the defect signal from an image line address and an image column address such that a pointer memory is addressed by the image line address, wherein the pointer memory contains a pointer for each of at least some of the image lines, the pointer addressing a defect column memory having stored therein column numbers of defective image columns; and

reading the column number from the defect column memory, comparing the column number with the column address, and forming therefrom the defect signal.

2. The method according to claim 1, which comprises

storing the pointer in the pointer memory and the column numbers in the defect column memory in such a way that

in a first case with multiple defect pixels in the columns of a line, the pointer belonging to the line addresses a memory cell in the defect column memory that contains a first of the associated column numbers, and the column numbers of the further defective columns of the line are deposited in increasing order in subsequent memory cells of the defect column memory;

in a second case with multiple defective pixels in a column, the pointers of multiple different lines refer to the same cell of the defect column memory with the associated defect column number; and

in a third case without defective pixels in a line, a cell in the defect column memory provided specifically for this case is addressed with the associated pointer

3. The method according to claim 1, which comprises, during a reading of a subimage, overreading and not correcting defect column numbers which are smaller than the column numbers of the subimage.

4. The method according to claim 1, which comprises identifying a last respective defect column of a respective

line with a continuation bit that is present one per defect column number.

5. A device for correcting defective pixels of an image sensor, comprising:

an input receiving input pixel data;

a defect memory unit addressable with an image line number and an image column number, and having an output;

an interpolator connected to said input and receiving the input pixel data and having an output;

a changeover switch connected to said interpolator and said defect memory unit and controlled by a defect signal, said changeover switch, in dependence on the defect signal, outputting either the input pixel data or output pixel data present at said output of said interpolator;

said defect memory device including a pointer memory, an address advancing device, and a defect column memory, whereby said pointer memory is addressed by the image line number and a content of a cell thus addressed addresses, via said address advancing device, said defect column memory, and said

defect column memory outputs a defect column number for the line with the relevant image line number; and

a comparator connected to compare the image column number with the defect column number from said defect column memory and to form therefrom the defect signal.

6. The device according to claim 5, wherein

said defect column memory is configured with one continuation bit per defect column number; and

wherein said address advancing unit is controllable by the continuation bit.

7. The device according to claim 5, which comprises a further comparator connected to ascertain whether the defect column number is smaller than the column number, and wherein said address advancing device advances the address of said defect column memory if the continuation bit is set.